

# SEM 2015

October 20-22, 2015, Göteborg, SWEDEN

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## Tuesday October 20, 2015

**08.45 - 09.00**     **Registration: outside Kollektorn**

**09.00 - 12.15**     **LECTURE HALL Kollektorn**

09.00 - 09.25     Welcome address and introductory remarks by the organizers  
*Lena Falk and Mats Halvarsson, Applied Physics, Chalmers*

09.25 - 10.05     Introduction to modern technologies in scanning electron microscopy  
*Mats Eriksson, Spectral Solutions, Sweden*

10.05 - 10.35     **COFFEE in the Canyon**

10.35 - 11.15     Low kV XEDS analyses  
*James Holland, Oxford Instruments, UK*

11.15 - 11.55     Introduction to DualBeams, FIB and 3D applications  
*Ellen Baken, FEI Company, The Netherlands*

**11.55 - 13.00**     **LUNCH in the Canyon**

**13.00 - 19.00**     **PRACTICALS**

13.00 - 14.15     Demonstrations -- Session I

14.15 - 14.45     **COFFEE in the Canyon**

14.45 - 17.15     Demonstrations -- Session II

17.15 - 19.00     Open Lab

**19.15**     **COURSE DINNER**

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## Wednesday October 21, 2015

### **09.00 - 12.00**    *LECTURE HALL KOLLEKTORN*

09.00 - 09.05    Introductory remarks by the organizers

09.05 - 09.45    The latest trends in focused ion beams  
*Antonin Doupal, TESCAN ORSAY HOLDING a.s., Czech Republic*

### **09.45 - 10.15**    **COFFEE in the Canyon**

10.15 - 10.45    High resolution imaging at low kV  
*Herbert Pavlicek, Carl Zeiss NTS GmbH, Germany*

10.45 - 11.15    Desktop SEM: Possibilities in imaging and analysis  
*Jeroen Smulders, Phenom-World BV., The Netherlands*

### **11.15 - 11.20**    **BREAK**

11.20 - 12.00    Specimen preparation for SEM and XEDS  
*Sten Sturefelt, Spectral Solutions, Sweden*

### **12.00 - 13.00**    **LUNCH in the Canyon**

### **13.00 - 20.00**    *PRACTICALS*

13.00 - 14.15    Demonstrations -- Session III

### **14.15 - 14.45**    **COFFEE in the Canyon**

14.45 - 17.15    Demonstrations -- Session IV

### **17.15**    **SANDWICHES and REFRESHMENTS**

17.15 - 20.30    Open Lab

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## Thursday October 22, 2015

### **09.00 - 12.00**    *LECTURE HALL KOLLEKTORN*

09.00 - 09.05    Introductory remarks by the organizers

09.05 - 09.45    Quantitative analysis by XEDS  
*James Holland, Oxford Instruments, UK*

### **09.45 - 10.15**    **COFFEE in the CANYON**

10.15 - 10.50    Transmission Kikuchi diffraction in SEM using on-axis detector  
*Laurie Palasse, Bruker Nano GmbH, Germany*

10.50 - 11.10    Work flow for SEM specimen preparation  
*Santiago Sevillano, Leica Microsystems*

11.10 - 11.30    Thin film analyses  
*Emanuel Katzmann, Jeol (Germany) GmbH*

11.30 - 11.40    Concluding remarks by the organizers

### **11.40 - 12.30**    **LUNCH in the CANYON**

### **12.30 - 16.30**    *PRACTICALS*

12.30 - 13.45    Demonstrations -- Session V

### **13.45 - 14.00**    **COFFEE in the CANYON**

14.00 - 16.30    Demonstrations -- Session VI

**16.30**    *End of Course*